



MIC Test Report

MIC LTE Test Report

For

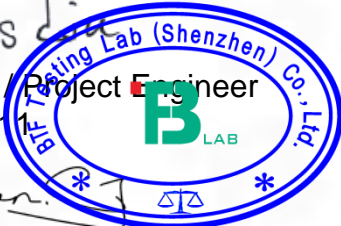
Applicant Name: Shenzhen DOOGEE Hengtong Technology CO.,LTD
B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park,
Address: No. 22, Dafu Industrial Zone, Guanlan Aobei Community,
Guanlan Street, Longhua New District, Shenzhen, Guangdong
China
EUT Name: Tablet
Brand Name: DOOGEE
Model Name: T20
Serial Model Name: Please refer to section 2.4

Issued By

Company Name: BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park,
Address: Tantou Community, Songgang Street, Bao'an District, Shenzhen,
China
Report Number: BTF250210R01002
Test Standards: Article 2, Paragraph 1, Item11-19, item 54.
Test Conclusion: Pass
Test Date: 2023-02-08 to 2023-02-15
Date of Issue: 2025-02-11

Prepared By:

Chris Liu
Chris Liu / Project Engineer
2025-02-11



Date:

Approved By:

Ryan.CJ / EMC Manager
2025-02-11

Note: All the test results in this report only related to the testing samples. Which can be duplicated completely for the legal use with approval of applicant; it shall not be reproduced except in full without the written approval of BTF Testing Lab (Shenzhen) Co., Ltd., All the objections should be raised within thirty days from the date of issue. To validate the report, you can contact us.

Revision History		
Version	Issue Date	Revisions Content
Rev-V0	2025-02-11	This report is base on the report No. BTF-BTF240408R00302, only the serial model name is changed,everything else is the same.
<i>Note:</i>	<i>Once the revision has been made, then previous versions reports are invalid.</i>	

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1. Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Test Location:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Description:	All measurement facilities used to collect the measurement data are located at F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

1.3 Laboratory Condition

Ambient Temperature:	20 °C to 25 °C
Ambient Relative Humidity:	45 % to 55 %
Ambient Pressure:	100 kPa to 102 kPa

1.4 Announcement

- (1) The test report reference to the report template version v0.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
- (6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

2. Product Information

2.1 Application Information

Company Name:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No. 22, Dafu Industrial Zone, Guanlan Aobei Community, Guanlan Street, Longhua New District, Shenzhen, Guangdong China

2.2 Manufacturer Information

Company Name:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No. 22, Dafu Industrial Zone, Guanlan Aobei Community, Guanlan Street, Longhua New District, Shenzhen, Guangdong China

2.3 Factory Information

Company Name:	Shenzhen DOOGEE Hengtong Technology CO.,LTD
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No. 22, Dafu Industrial Zone, Guanlan Aobei Community, Guanlan Street, Longhua New District, Shenzhen, Guangdong China

2.4 General Description of Equipment under Test (EUT)

EUT Name	Tablet
Under Test Model Name	T20
Series Model Name	T36, T10S, Tab A9, U9, T30Pro, T30S, U11, Tab G6, U11 Pro, T20 Ultra, Tab E3 Pro, Tab A9+, T30 Ultra, Tab E3Max, Tab A9Pro, Tab E3, Tab E3+, Tab G6S, Tab G6+, T20Mini, Tab A9 Pro+, U10, T30 Max, V Pad, T10W
Description of Model name differentiation	They are the same product, but the model name and color are different. Everything else is the same.
Hardware Version	T30-T616-V2.0
Software and Firmware Version	DOOGEE-T20-EEA_18-Android 12.0

2.5 Technical Information

Product Feature & Specification		
Type Emission	D1A,D1B,D1C,D1D,D1F,D1X,W7D, G1A,G1B,G1C,G1D,G1F,G1X,G7D	
Channel Spacing	100kHz	
Support Band / 3GPP Band	700M Band	■ Band 28
	850M Band	□ Band 5 □ Band 18 ■ Band 19 □ Band 26
	900M Band	■ Band 8
	1.5G Band	□ Band 11 □ Band 21
	1.7G Band	■ Band 3 □ Band 9
	2.1G Band	■ Band 1
Frequency Range	Band 1 5MHz BW : 1927.2MHz ~ 1977.5MHz 10MHz BW : 1934.7MHz ~ 1975.0MHz 15MHz BW : 1942.2MHz ~ 1972.5MHz 20MHz BW : 1949.7MHz ~ 1970.0MHz	
	Band 3 5MHz BW : 1747.4MHz ~ 1782.4MHz 10MHz BW : 1749.9MHz ~ 1779.9MHz 15MHz BW : 1752.4MHz ~ 1777.4MHz 20MHz BW : 1754.9MHz ~ 1774.9MHz	
	Band 8 5MHz BW : 902.5MHz ~ 912.5MHz 10MHz BW : 905.0MHz ~ 910.0MHz	
	Band 41 5MHz BW : 2547.5MHz ~ 2652.5MHz 10MHz BW : 2550.0MHz ~ 2650.0MHz 20MHz BW : 2555.0MHz ~ 2645.0MHz	
Declaration RF Output Power	199.53mW (23 dBm)	
Modulation Type	QPSK, 16QAM	
E-UTRA Category	Category 3	
SIM Card	2 SIM Cards Note: SIM Card1 and SIM Card2 have been tested, Only shown the worst result (SIM Card1) in the report.	
Antenna Type	PIFA Antenna (Main and DIV ANT) Note: The two antennas are transmitted from the same port and only one works at the same time.	
Antenna Gain	Band 1: 0.19dBi Band 3: 0.23dBi Band 8: 0.12dBi Band 41: 0.39dBi	
Power Source	□ Commercial power	N/A
	■ External Power Source	DC 5 V

	<input checked="" type="checkbox"/> Li-ion BATTERY PACK	DC 3.8V, 8300mAh
	<input type="checkbox"/> UMBattery	N/A

Test Channel List

Operating Bands	UL Channel	Channel Bandwidth (MHz)	UL Channel No.	UL Frequency (MHz)
Band 1	Low Channel	5	18072	1927.2
		10	18147	1934.7
		15	18222	1942.2
		20	18297	1949.7
	Middle Channel	5	18324	1952.4
		10	18349	1954.9
		15	18374	1957.4
		20	18399	1959.9
	High Channel	5	18575	1977.5
		10	18550	1975
		15	18525	1972.5
		20	18500	1970
Band 3	Low Channel	5	19574	1747.4
		10	19599	1749.9
		15	19624	1752.4
		20	19649	1754.9
	Middle Channel	5/10/15/20	19749	1764.9
	High Channel	5	19924	1782.4
		10	19899	1779.9
		15	19874	1777.4
		20	19849	1774.9
	Band 8	Low Channel	5	21675
10			21700	905
Middle Channel		5/10	21725	907.5
High Channel		5	21775	912.5
		10	21750	910
Band 41	Low Channel	5	40165	2547.5
		10	40190	2550.0
		20	40240	2555.0
	Middle Channel	5/10/20	40690	2600.0
	High Channel	5	41215	2652.5
		10	41190	2650.0
		20	41140	2645.0

3. Summary of Test Results

Test items and the results are as follows:

Requirement	Report Section	Result
Frequency Tolerance	5.1.1	PASS
RF Output Power Tolerance	5.1.2	PASS
Occupied Bandwidth	5.1.3	PASS
Adjacent Channel Leakage Power	5.1.4	PASS
Unwanted Emission Strength in Out-band Area	5.1.5	PASS
Unwanted Emission Strength in Spurious Area	5.1.6	PASS
Secondarily Emitted Radio Wave Strength	5.1.7	PASS
Leakage Power at No-carrier Transmission	5.1.8	PASS
Comprehensive Operation Test	5.1.9	PASS
Construction Protection Confirmation Method	5.1.10	PASS

Note:

1. PASS: Test item meets the requirement.
2. Fail: Test item does not meet the requirement.
3. N/A: Test case does not apply to the test object.
4. The test result judgment is decided by the limit of test standard.

3.1 Uncertainty of Test

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in TR 100 028-1, and TR 100 028-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Parameters	Uncertainty
RF power, conducted	± 0.90 dB
All emissions, radiated	± 5.36 dB
Unwanted Emissions, conducted	± 0.90 dB
Voltage (DC)	± 3.6 %
Temperature	$\pm 0.82^{\circ}\text{C}$
Humidity	± 4.1 %

4. Test Configuration

4.1 Environment Condition

During the measurement, the normal environment conditions were within the listed ranges

Relative Humidity (%)	45% to 55%	
Atmospheric Pressure (kPa)	100 kPa to 102 kPa	
Temperature	NT (Normal Temperature)	+22°C to +25°C
	LT (Low Temperature)	-10°C
	HT (High Temperature)	+40°C
Working Voltage of the EUT	NV (Normal Voltage)	3.8V
	LV (Low Voltage)	3.42 V
	HV (High Voltage)	4.18 V

The RF unit is supplied DC 1.8V. The fluctuation of input voltage to the circuit of RF unit of test equipment is under $\pm 1\%$, when input voltage DC 3.8V is fluctuated $\pm 10\%$, so all measurement has been conducted by only rated voltage.

DC Input	RF_IC Input	Rate of fluctuation(%)
3.80V	1.8V	0.0
3.42V	1.8V	0.0
4.18V	1.8V	0.0

4.2 Test Equipment List

Conducted Method Test							
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Cal. By	Use
MXA Signal Analyzer	KEYSIGHT	N9020A	MY50410020	2022.11.24	2023.11.23	Guangzhou LiSai Metrology & Test Co., Ltd.	<input checked="" type="checkbox"/>
WIDEBAND RADIO COMMUNICATION TESTER	Rohde & Schwarz	CMW500	161997	2022.11.24	2023.11.23	Guangzhou LiSai Metrology & Test Co., Ltd.	<input checked="" type="checkbox"/>
Adjustable Direct Current Regulated Power Supply	Dongguan Tongmen Electronic Technology Co., LTD	etm-6050c	20211026123	2022.11.24	2023.11.23	Guangzhou LiSai Metrology & Test Co., Ltd.	<input checked="" type="checkbox"/>
Programmable constant	ZZCKONG	ZZ-K02A	20210928007	2022.11.24	2023.11.23	Guangzhou LiSai	<input checked="" type="checkbox"/>

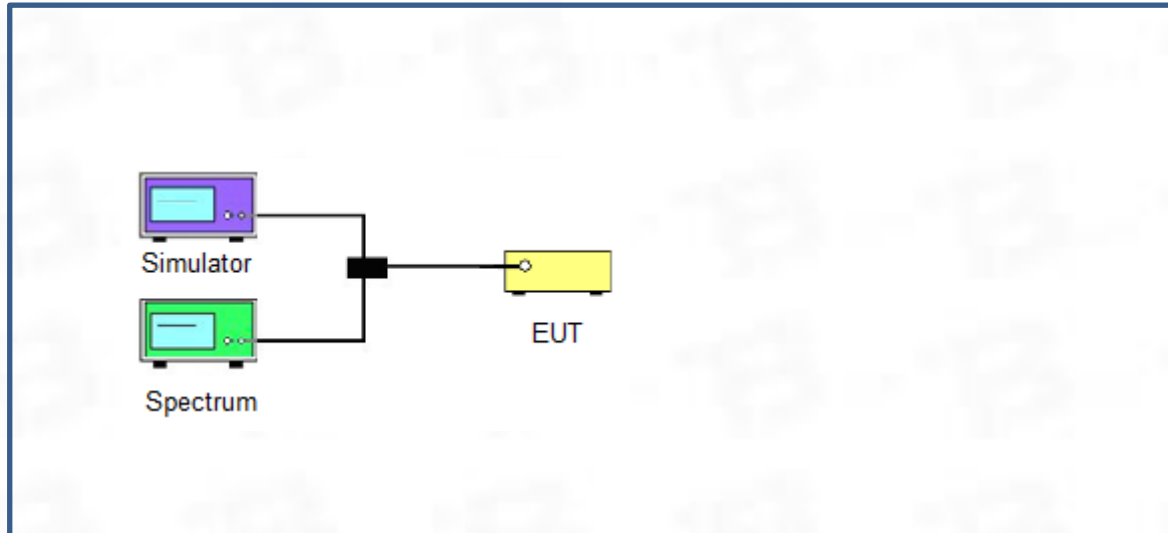
temperature and humidity box						Metrology & Test Co., Ltd.	
RF Sensor Unit	Techy	TR1029-2	/	/	/	/	☒
RF Control Unit	Techy	TR1029-1	/	/	/	/	☒
RFTest software	/	V1.00	/	/	/		☒

Remark:

1. Calibration conducted by the National Institute of Information and Communications Technology (NICT) in Japan (hereinafter referred to as *NICT*) or a designated calibration agency under Article 102-18 paragraph (1) in JRL.
2. Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Act (Act No.51 of 1992)
3. Calibration conducted in countries except Japan, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
4. Calibration, etc. conducted by using measuring instruments and other equipment listed in the right column of appended table No. 3, which shall have been given any type of calibration, etc. listed above from (2) to (4).
From JRL Article 24-2, paragraph 4, Item 2
All calibration information is from Guangzhou LiSai Metrology & Test Co., Ltd..

4.3 Test Setup

Test Setup 1 For antenna port Test



5. Test Items

5.1 Test Results and Measurement Data

5.1.1 Frequency Tolerance

5.1.1.1 Limit

$$\leq \pm(0.1 \times f_c \times 10^{-6} + 15) \text{ Hz}$$

5.1.1.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.1.3 Test Procedures

Follow 3GPP Standard TS36.521-1 Section 6.5.1.

5.1.1.4 Test Result

Please refer to the appendix B of test data.

5.1.2 RF Output Power and Output Power Tolerance Measurement

5.1.2.1 Limit

Item	Limits
Output Power / E.I.R.P	$\leq 200\text{mW}$ (23dBm) / $\leq 26\text{dBm}$
Output Power Tolerance	+87% ~ -47%

5.1.2.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.2.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.2.2
 $\text{Output Power(dBm)} = P(\text{dBm}) = P_{\text{Linear}}(\text{mW})$
 $\text{E.I.R.P(dBm)} = P(\text{dBm}) + \text{Peak Antenna Gain(dBi)}$
 $\text{Tolerance} = (P_{\text{Linear}} - 200) / 200 \times 100\%$

5.1.2.4 Test Result

Please refer to the appendix B of test data.

5.1.3 Occupied Bandwidth Measurement

5.1.3.1 Limit

Item	Limits
Occupied Band Width	$\leq 5\text{MHz}$ (for Bandwidth = 5MHz) $\leq 10\text{MHz}$ (for Bandwidth = 10MHz) $\leq 15\text{MHz}$ (for Bandwidth = 15MHz) $\leq 20\text{MHz}$ (for Bandwidth = 20MHz)

5.1.3.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.3.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.6.1.

5.1.3.4 Test Result

Please refer to the appendix B of test data.

5.1.4 Adjacent Channel Leakage Power Measurement

5.1.4.1 Limit

Item	Band Width	Limit
ACLR	5 MHz	$\pm 5\text{MHz}$ $\leq -29.2\text{dBc}/4.5\text{MHz}$ or -
		50dBm/4.5MHz
		$\pm 5\text{MHz}$ $\leq -32.2\text{dBc}/3.84\text{MHz}$ or -
		50dBm/3.84MHz
	10 MHz	$\pm 10\text{MHz}$ $\leq -35.2\text{dBc}/3.84\text{MHz}$ or -
		50dBm/3.84MHz
		$\pm 10\text{MHz}$ $\leq -29.2\text{dBc}/9\text{MHz}$ or -
		50dBm/9MHz
	15 MHz	$\pm 7.5\text{MHz}$ $\leq -32.2\text{dBc}/3.84\text{MHz}$ or -
		50dBm/3.84MHz
		$\pm 12.5\text{MHz}$ $\leq -35.2\text{dBc}/3.84\text{MHz}$ or -50dBm/3.84MHz
		50dBm/3.84MHz
	20 MHz	$\pm 15\text{MHz}$ $\leq -29.2\text{dBc}/13.5\text{MHz}$ or -
		50dBm/13.5MHz
		$\pm 10\text{MHz}$ $\leq -32.2\text{dBc}/3.84\text{MHz}$ or -
		50dBm/3.84MHz
	20 MHz	$\pm 15\text{MHz}$ $\leq -35.2\text{dBc}/3.84\text{MHz}$ or -
		50dBm/3.84MHz
		$\pm 20\text{MHz}$ $\leq -29.2\text{dBc}/18\text{MHz}$ or -
		50dBm/18MHz
	20 MHz	$\pm 12.5\text{MHz}$ $\leq -32.2\text{dBc}/3.84\text{MHz}$ or -50dBm/3.84MHz
		$\pm 17.5\text{MHz}$ $\leq -35.2\text{dBc}/3.84\text{MHz}$ or -50dBm/3.84MHz

5.1.4.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.4.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.6.2.3

5.1.4.4 Test Result

Please refer to the appendix B of test data.

5.1.5 Unwanted Emission Strength in Out-band Area Measurement

5.1.5.1 Limit

Item	Band Width	Limit
Unwanted Emission Strength in Out-band Area	5 MHz	$\Delta f < 1\text{MHz} \leq -13.5\text{dBm}/30\text{kHz}$ $1\text{MHz} \leq \Delta f < 5\text{MHz} \leq -8.5\text{dBm}/\text{MHz}$ $5\text{MHz} \leq \Delta f < 6\text{MHz} \leq -11.5\text{dBm}/\text{MHz}$ $6\text{MHz} \leq \Delta f < 10\text{MHz} \leq -23.5\text{dBm}/\text{MHz}$
	10 MHz	$\Delta f < 1\text{MHz} \leq -16.5\text{dBm}/30\text{kHz}$ $1\text{MHz} \leq \Delta f < 5\text{MHz} \leq -8.5\text{dBm}/\text{MHz}$ $5\text{MHz} \leq \Delta f < 10\text{MHz} \leq -11.5\text{dBm}/\text{MHz}$ $10\text{MHz} \leq \Delta f < 15\text{MHz} \leq -23.5\text{dBm}/\text{MHz}$
	15 MHz	$\Delta f < 1\text{MHz} \leq -18.5\text{dBm}/30\text{kHz}$ $1\text{MHz} \leq \Delta f < 5\text{MHz} \leq -8.5\text{dBm}/\text{MHz}$ $5\text{MHz} \leq \Delta f < 15\text{MHz} \leq -11.5\text{dBm}/\text{MHz}$ $15\text{MHz} \leq \Delta f < 20\text{MHz} \leq -23.5\text{dBm}/\text{MHz}$
	20 MHz	$\Delta f < 1\text{MHz} \leq -19.5\text{dBm}/30\text{kHz}$ $1\text{MHz} \leq \Delta f < 5\text{MHz} \leq -8.5\text{dBm}/\text{MHz}$ $5\text{MHz} \leq \Delta f < 20\text{MHz} \leq -11.5\text{dBm}/\text{MHz}$ $20\text{MHz} \leq \Delta f < 25\text{MHz} \leq -23.5\text{dBm}/\text{MHz}$

5.1.5.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.5.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.6.2.2

5.1.5.4 Test Result

Please refer to the appendix B of test data.

5.1.6 Unwanted Emission Strength in Spurious Area Measurement

5.1.6.1 Limit

Item	Limits
General	9kHz ~ 150kHz \leq -36dBm/kHz 150kHz ~ 30MHz \leq -36dBm/10kHz 30MHz ~ 1000MHz \leq -36dBm/100kHz 1000MHz ~ 12.75GHz \leq -30dBm/1MHz
	1844.9MHz ~ 1879.9MHz \leq -50dBm/MHz 1884.5MHz ~ 1915.7MHz \leq -41dBm/300kHz 2010MHz ~ 2025MHz \leq -50dBm/MHz 2110MHz ~ 2170MHz \leq -50dBm/MHz
For 2G & 1.7G Band	860MHz ~ 890MHz \leq -50dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -50dBm/MHz
For 1744.9MHz ~ 1749.9MHz	773MHz ~ 803MHz \leq -50dBm/MHz 860MHz ~ 890MHz \leq -50dBm/MHz 945MHz ~ 960MHz \leq -50dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -50dBm/MHz 1839.9MHz ~ 1844.9MHz \leq -50dBm/MHz
For 1.5G Band	860MHz ~ 890MHz \leq -50dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -30dBm/MHz (for 5MHz System) \leq -35dBm/MHz (for 10MHz/15MHz/20MHz System)
For 900M Band	860MHz ~ 890MHz \leq -40dBm/MHz 945MHz ~ 960MHz \leq -50dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -50dBm/MHz
For 800M Band	860MHz ~ 890MHz \leq -40dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -50dBm/MHz
For 700M Band	470MHz ~ 710MHz \leq -26.2dBm/6kHz 773MHz ~ 803MHz \leq -50dBm/MHz 860MHz ~ 890MHz \leq -50dBm/MHz 945MHz ~ 960MHz \leq -50dBm/MHz 1475.9MHz ~ 1510.9MHz \leq -50dBm/MHz

5.1.6.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.6.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.6.3

5.1.6.4 Test Result

Please refer to the appendix B of test data.

5.1.7 Secondly Emitted Radio Wave Strength Measurement

5.1.7.1 Limit

Item	Limits
Secondarily Emitted Radio Wave Strength	30MHz ~ 1000MHz \leq -57dBm/100kHz
	1000MHz ~ 12.75GHz \leq -47dBm/1MHz

5.1.7.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 1. The photo of test setup please refer to Test Setup Document.

5.1.7.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 7.9.

5.1.7.4 Test Result

Please refer to the appendix B of test data.

5.1.8 Leakage Power at No-carrier Transmission Measurement

5.1.8.1 Limit

Item	Band Width	Limit
Leakage Power at No-carrier Transmission	5 MHz	$\leq -48.5\text{dBm}/4.5\text{MHz}$
	10 MHz	$\leq -48.5\text{dBm}/9\text{MHz}$
	15 MHz	$\leq -48.5\text{dBm}/13.5\text{MHz}$
	20 MHz	$\leq -48.5\text{dBm}/18\text{MHz}$

5.1.8.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 2. The photo of test setup please refer to Test Setup Document.

5.1.8.3 Test Procedures

Follow 3GPP Standard TS 36.521-1 Section 6.3.3

5.1.8.4 Test Result

Please refer to the appendix B of test data.

5.1.9 Comprehensive Operation Test

5.1.9.1 Limit

1. Automatic identification function

The transmitter of each land mobile station communicating with a base station shall be identified automatically by a base station

2. Automatic channel switching function

It is preformed that has automatically channel switching communicating channel from base station to other base station.

3. Traffic control function

The area in accordance is provided for the service of base station. The area resulting electric field strength required to provide for the service. It can be subdivided to match the traffic of the area.

4. Automatic power control function

Based on the control information from the base station or the measurement of the received power of the radio wave from the base station, It has a function for automatically controlling that antenna power is the minimum.

5.1.9.2 Test Setup

Please refer to 4.3 section description of test setup of test setup 2. The photo of test setup please refer to Test Setup Document.

5.1.9.3 Test Result

All test methods meet the above upper limit requirements.

5.1.10 Construction Protection Confirmation Method

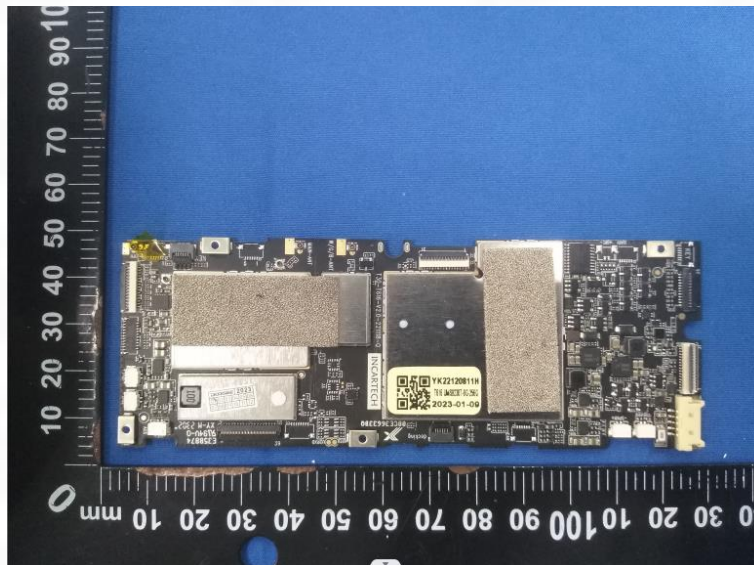
5.1.10.1 Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily

5.1.10.2 Test Method

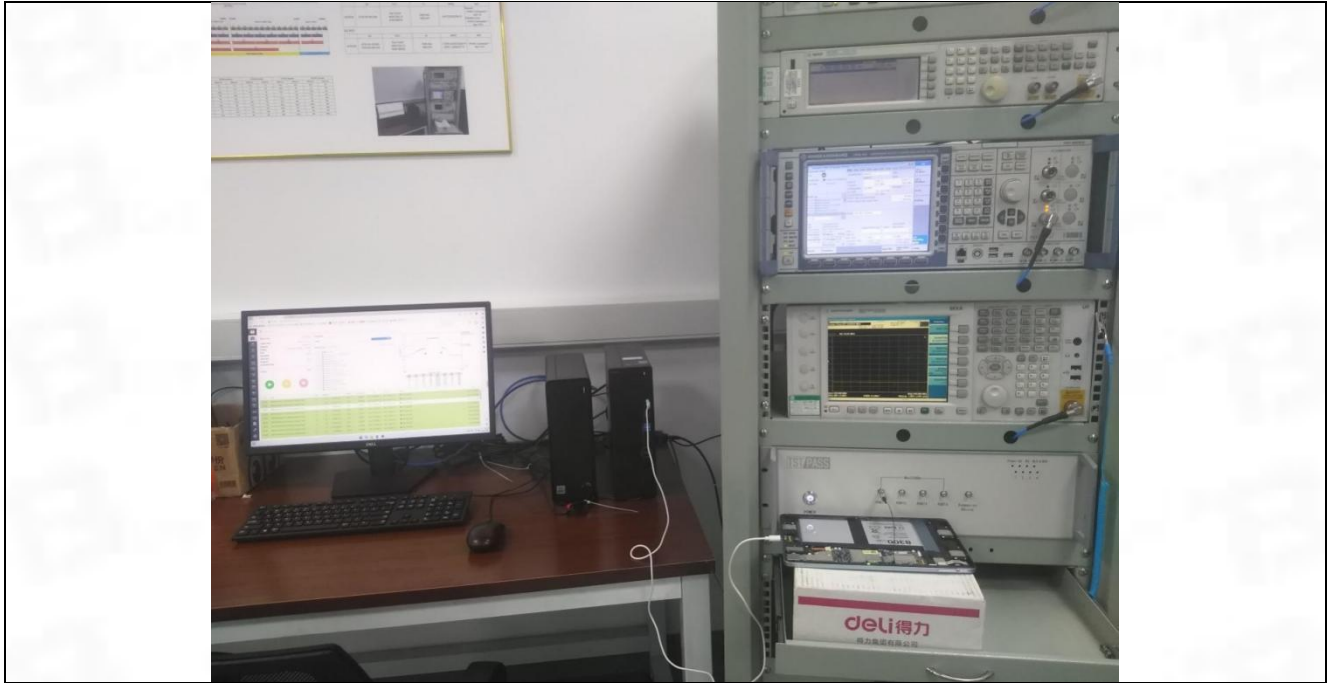
<input type="checkbox"/>	Sealed with special screws.
<input type="checkbox"/>	Plastic chassis is being welded using ultrasonic waves.
<input checked="" type="checkbox"/>	Chassis is glued using a special adhesive.
<input type="checkbox"/>	Metal covers are spot-fused.
<input type="checkbox"/>	Cover is specially interlocked.
<input checked="" type="checkbox"/>	RF and Modulation components are covered with shielding case and this shielding case is soldered.
<input type="checkbox"/>	Shield case is welded at RF and modulation parts, and ID-ROM is welded using the BGA Method.
<input type="checkbox"/>	Shield case is welded at RF and modulation parts, and ID-ROM is glued at its lead with a special adhesive.
<input type="checkbox"/>	Shield case is welded at RF and modulation parts, and ID-ROM is glued with a non-transparent laminating agent.
<input type="checkbox"/>	Other :

5.1.10.3 Test Result



EUT TEST SETUP PHOTOS

SETUP PHOTOS



EUT EXTERNAL PHOTOS

Please refer to Report No. BTF250210R01001.

EUT INTERNAL PHOTOS

Please refer to Report No. BTF250210R01001



BTF Testing Lab (Shenzhen) Co., Ltd.

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